

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1114

SERIAL NO.

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1765

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TSP	AA	4,568,565	02/1986	GUPTA ET AL.	427	53.1	8/14/84
TSP	AB	4,971,655	11/1990	STEFANO ET AL.	156	659.1	12/26/89
TSP	AC	5,240,739	08/1993	DOAN ET AL.	427	126.1	8/7/92
TSP	AD	5,376,405	12/1994	DOAN ET AL.	427	126.1	4/5/93
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

TSP	AR		ILDEREM, V., et al., "Optimized Deposition Parameters for Low Pressure Chemical Vapor Deposited
			Titanium Silicide", <i>Massachusetts Institute of Technology</i> , Vol. 135, No. 10, pp. 2590-96 (2/1988)
TSP	AS		NAGABUSHNAM, R.V., et al., "Kinetics and Mechanism Of The C49 to C54 Titanium Disilicide Phase Transformation
			Formation In Nitrogen Ambient", 5 pages (Published 11/1995)
	AT		

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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-1114SERIAL NO.
09/233,377

LIST OF ART CITED BY APPLICANT

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APPLICANT
Micron Technology, Inc.FILING DATE
January 18, 1999

GROUP

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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TSP	AA	5,997,634	12/7/99	Sandhu et al.	117	3	10/14/96
	AB						
	AC						
	AD						
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	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

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	AN							
	AO							
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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